# OpenOCD - Beyond Simple Software Debugging

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## Why I use OpenOCD?

- Reverse engineering and for fun
  - This is the main motivation behind this talk
- Debugging
- Testing



## My reverse engineering rules

- Investigate public materials
  - Standards
  - Documentation
  - Patterns
- Try to apply gained knowledge to similarly purposed systems
  - New technology is expensive and vendors are trying to reuse as much as possible
- Assumptions are OK!



- Everyone who used OpenOCD for software debugging or reverse engineering
- Everyone who has time to use OpenOCD on unsupported or untested HW
- Everyone who is interested in exploring HW from JTAG perspective

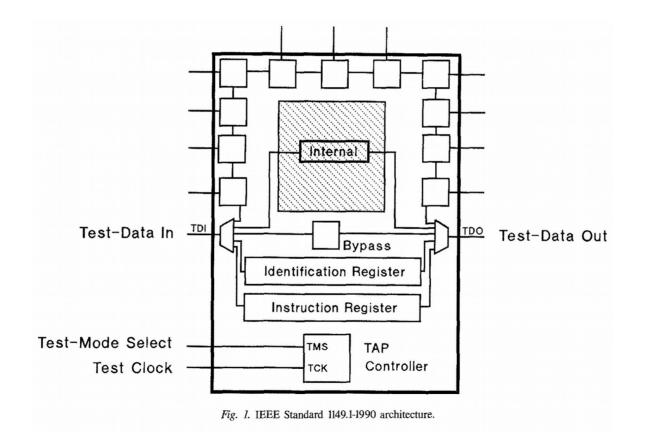


# History of JTAG

- 1986 Philips forms Joint European Test Action Group
- 1990 IEEE Standard 1149.11990 published
- JOURNAL OF ELECTRONIC TESTING: Theory and Applications, 2, 1125 (1991)

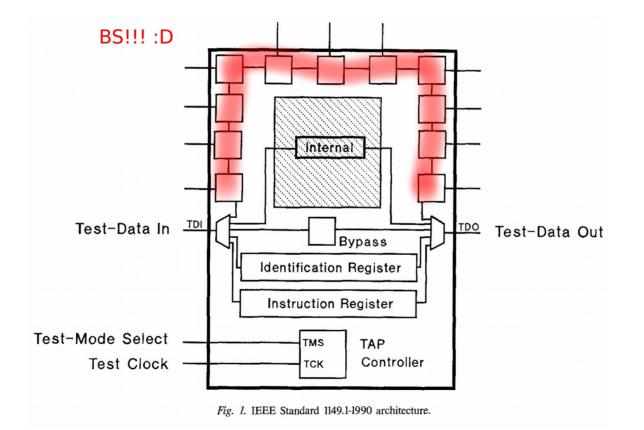


#### boundary scan





## **Boundary Scan**







- Now 2018, 28 years later...
- We are still using this technology but have no idea how to use it for the original purpose – boundary scan!
- Let's go back to the roots!!! ;)



### What is **BSDL**

- Boundary Scan Description Language
- 1149.1b-1994 "Supplement to IEEE Std 1149.1-1990, IEEE standard test access port and boundary-scan architecture"
- 1149.1-2001 "IEEE standard test access port and boundary-scan architecture"



## BSDL Example 1

* File Name	: STM32F302 F	303_B_C_LQFP100.bsd	7
	: STMicroelec		3
* Version	: V1.0		7
* Date	: 13-August-2	015	7
* Description	: Boundary Sc	an Description Language (BSDL) file for the	*
*		303_B_C_LQFP100 Microcontrollers.	*
***********	******	***************************************	***
* THE PRESENT SC	OFTWARE WHICH IS FO	R GUIDANCE ONLY AIMS AT PROVIDING CUSTOMERS	7
* WITH CODING IN	FORMATION REGARDIN	G THEIR PRODUCTS IN ORDER FOR THEM TO SAVE TIM	E. *
* AS A RESULT, S	STMICROELECTRONICS	SHALL NOT BE HELD LIABLE FOR ANY DIRECT,	7
		S WITH RESPECT TO ANY CLAIMS ARISING FROM THE	*
		THE USE MADE BY CUSTOMERS OF THE CODING	*
		CONNECTION WITH THEIR PRODUCTS.	2
		***************************************	***
	e has been syntaxed	checked and validated by:	
*			
* GOEPEL Syntax	hecker Version 3.1		7
***************	***************	***************************************	***
	303_B_C_LQFP100 is		
		lt device package selected.	
		"LQFP100_PACKAGE");	
	eclares all the por	ts in the design.	
port (			
BOOTO	: in bit;		
JTDI	: in bit;		
JTMS			
JTCK			
JTRST JTDO	: out bit;		
NRST	: in bit;	modification to add COMPLIANCE PATTERNS	
ГСИИ	: th bit;	MOULT COLLON TO AND COMPLIANCE_PATTERNS	



#### **BSDL Example 2**

attribute INSTRUCTION\_LENGTH of STM32F302\_F303\_B\_C\_LQFP100: entity is 5;

-- Specifies the boundary-scan instructions implemented in the design and their opcodes.

attribute INSTRUCTION\_OPCODE of STM32F302\_F303\_B\_C\_LQFP100: entity is
"BYPASS (11111)," &
"EXTEST (00000)," &
"SAMPLE (00010)," &
"PRELOAD (00010)," &
"IDCODE (00001)":

- -- Specifies the bit pattern that is loaded into the instruction register when the TAP controller
- -- passes through the Capture-IR state. The standard mandates that the two LSBs must be "01". The
- -- remaining bits are design specific.

attribute INSTRUCTION\_CAPTURE of STM32F302\_F303\_B\_C\_LQFP100: entity is "XXX01";

-- Specifies the bit pattern that is loaded into the DEVICE\_ID register during the IDCODE -- instruction when the TAP controller passes through the Capture-DR state.

attribute IDCODE\_REGISTER of STM32F302\_F303\_B\_C\_LQFP100: entity is "XXXX" & -- 4-bit version number "0110010000100010" & -- 16-bit part number "00000100000" & -- 11-bit identity of the manufacturer "1"; -- Required by IEEE Std 1149.1

-- This section specifies the test data register placed between TDI and TDO for each implemented -- instruction.

```
attribute REGISTER_ACCESS of STM32F302_F303_B_C_LQFP100: entity is
"BYPASS (BYPASS)," &
"BOUNDARY (EXTEST, SAMPLE, PRELOAD)," &
"DEVICE_ID (IDCODE)";
```



## BSDL Example 3

attribute BOUNDARY\_LENGTH of STM32F302\_F303\_B\_C\_LQFP100: entity is 250;

TI	following list specifies the characteristics of each cell in the boundary scan register from	m
TI	to TDO. The following is a description of the label fields:	
	num : Is the cell number.	
	cell : Is the cell type as defined by the standard.	
	port : Is the design port name. Control cells do not have a port name.	
	function: Is the function of the cell as defined by the standard. Is one of input, output2,	,
	output3, bidir, control or controlr.	
	safe : Specifies the value that the BSR cell should be loaded with for safe operation	
	when the software might otherwise choose a random value.	
	ccell : The control cell number. Specifies the control cell that drives the output enable	e
	for this port.	
	disval : Specifies the value that is loaded into the control cell to disable the output	
	enable for the corresponding port.	
	rslt : Resulting state. Shows the state of the driver when it is disabled.	

attribute BOUNDARY REGISTER of STM32F302 F303 B C LOFP100: entity is

 num	cell	port	function	safe	[ccell	disval	rslt]		
"249	(BC_1,	*,	CONTROL,	1),					&
"248	(BC_1,	PE2,	OUTPUT3,	Х,	249,	1,	Z),	п	&
"247	(BC_4,	PE2,	INPUT,	X),					&
"246	(BC_1,	*,	CONTROL,	1),					&
"245	(BC_1,	PE3,	OUTPUT3,	х,	246,	1,	Z),		&
"244	(BC_4,	PE3,	INPUT,	X),				п	&
"243	(BC 1,	*,	CONTROL,	1),					&
"242	(BC_1,	PE4,	OUTPUT3,	Х,	243,	1,	Z),		&
"241	(BC_4,	PE4,	INPUT,	X),				п	&



### The road map

- How to get JTAG access on modern SoCs.
- Exploring diferent TAPs and seeking BS register
- Reading BSDL files.
- Unfriendly vendor and no BSDL file, trying to reverse engineer it.
- Practical example.
- Combine CPU and BS tests? Is it possible?



# Exploring JTAG port

- In the perfect world, we would have a dedicated JTAG connector in accordance with some valid specification, working all the time from power on till power off.
- The reality is different:
  - In many cases JTAG pins are enabled by the SoC ROM, with some delay after power on (or power cycle)
  - The pins have JTAG functionality only limited time after some event
  - Many TAPs and DAPs with some differences from default or wellknown specifications

Welcome to the JTAG zoo!



## **Getting JTAG access**

- There are two states:
  - It just works!
  - Go with me, I'll show you how some vendors do it! :D



## Exploring JTAG port (time frames)

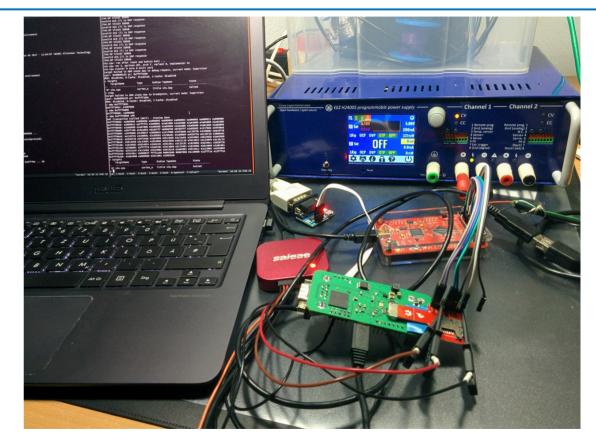


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- Most of the Allwinner SoCs have JTAG multiplexed with SD card signals. It is not a secret, but not welldocumented
- This port can be used only within a short time frame:
  - Some X millisecs after power on JTAG gets enabled
  - X+Yms after power on this port is switched from JTAG to SD, so we have just a small window to access JTAG



- Remote controllable bench power supply and logic analyser are your friends
- Use adapter\_nsrst\_delay
- Increase adapter\_khz speed to fit to narrow time frame
- Add some pull-up resistor to the TDI line and measure it





1. no pull-ups, 2. pull-ups on 1,2,3,4

800				Saleae Lo	ogic 1.2.29 Beta -	[Connected] – [50,	00 MHz Digital, 10	00,0 s]			Opt	ions 🔻
									2 s : 460 ms		Annotations	+
oture	× .		🗬 +3 ms 🚱								🔻 🦿 🤇 Timing Marker Pair	
	<b>\$</b> + <del>5</del>										A1 - A2   = 0,4719400000 n	
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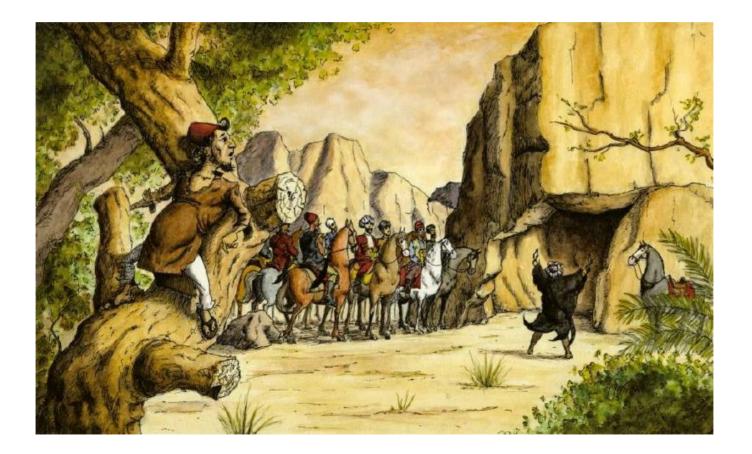
												Annotations	+
	<b>T</b>	15	+5 🛺	+6 ms							+9 ms	Timing Marker Pair	▼ ☆
	<b>\$</b> +₹											<u>A1</u> - <u>A2</u>   = 0,4787400	
	<b>\$</b> +₹			[				[					
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	✿ + <sub>₹</sub>												
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Start											
Start	× 1		+5 🐺 🦉	+6 ms							+9 ms
00 Vcc	¢ +5										
01 D0/TDI	¢ +7										
02 D1/TMS	¢ +f										
03 D2/TCK	<b>\$</b> +7										
04 CMD/TD0	¢ +5										
	"-	PW O	N								
		PW O J				~8ms					



## Exploring JTAG port (Open Sesame)

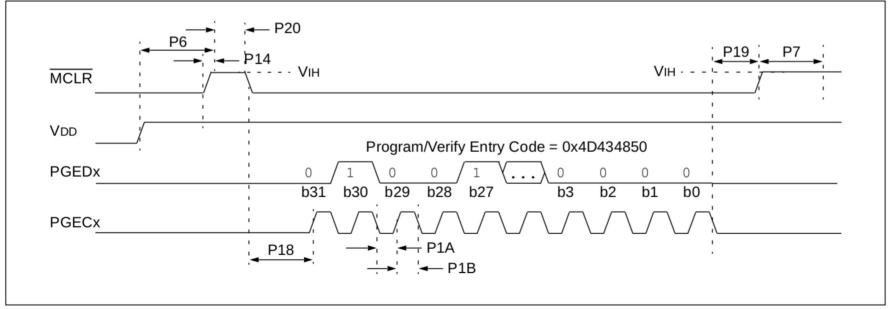


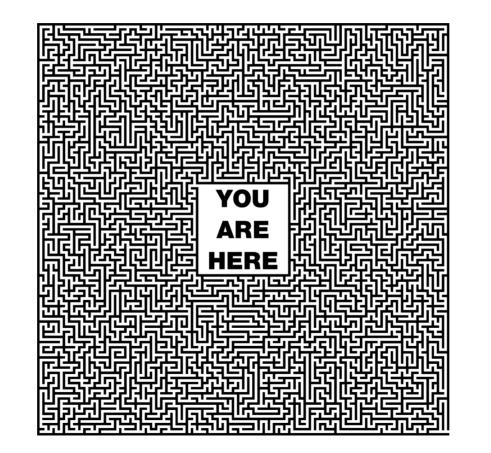


## Exploring JTAG port (Open Sesame)

 Nicely documented JTAG/ICSP interfaces made by Microchip for PIC32xx series

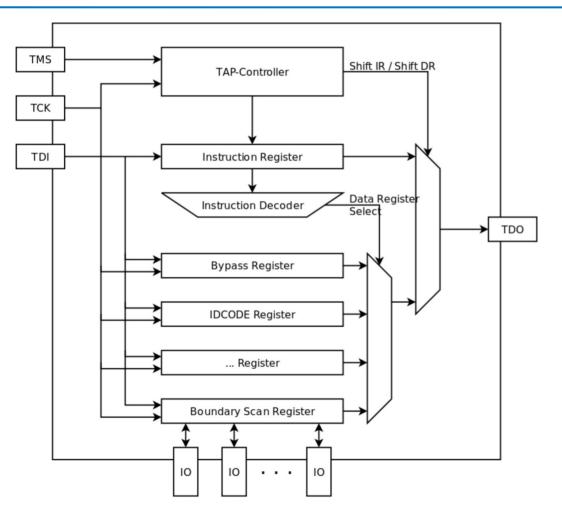
FIGURE 7-1: ENTERING ENHANCED ICSP<sup>™</sup> MODE







# Exploring the internals



- Let's assume we got access to the SoC, what can we explore?
- TAP test access port
- Typical instructions provided by a TAP:
  - IDCODE
  - Boundary scan
  - Bypass

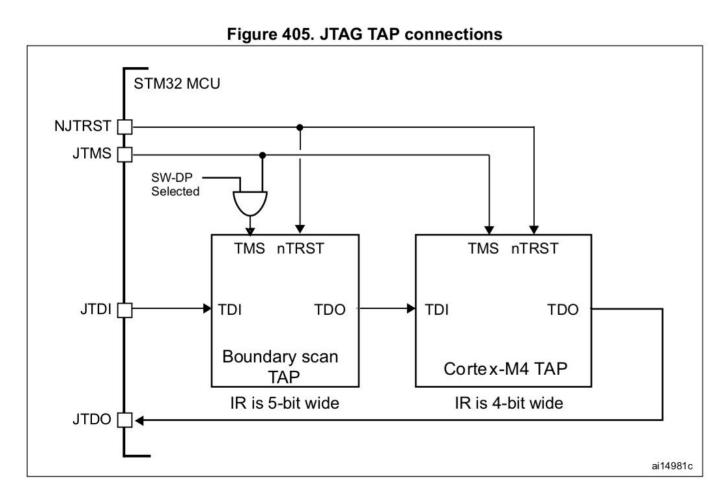


## Exploring the internals

- The times they are a-changin', after 28 years internals are a bit more complicated
- Let's take as example STM32 and do following steps:
  - Find the right TAP
  - Find the right Instruction
  - Find the right Bits



## Find the right TAP





#### Find the right Instruction

attribute INSTRUCTION\_LENGTH of STM32F302\_F303\_B\_C\_LQFP100: entity is 5;

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-- This section specifies the test data register placed between TDI and TDO for each implemented -- instruction.

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attribute REGISTER_ACCESS of STM32F302_F303_B_C_LQFP100: entity is
"BYPASS (BYPASS)," &
"BOUNDARY (EXTEST, SAMPLE, PRELOAD)," &
"DEVICE_ID (IDCODE)";
```



# Find the right Bits

"154	(BC_4,	PE7,	INPUT,	X),				" &
"153	(BC_1,	*,	CONTROL,	1),				"&
"152	(BC_1,	PE8,	OUTPUT3,	Х,	153,	1,	Z),	"&
"151	(BC_4,	PE8,	INPUT,	X),				" &
"150	(BC_1,	*,	CONTROL,	1),				" &
"149	(BC_1,	PE9,	OUTPUT3,	Х,	150,	1,	Z),	"&
"148	(BC_4,	PE9,	INPUT,	X),		100000	600000000	"&
"147	(BC_1,	*,	CONTROL,	1),				" &
"146	(BC_1,	PE10,	OUTPUT3,	Х,	147,	1,	Z),	" &
"145	(BC 4,	PE10,	INPUT,	X),	1.53	100	13.07%	" &
"144	(BC_1,		CONTROL,					
"143	(BC_1,	PE11,	OUTPUT3,	х,	144,		Z),	
"142	(BC_4,	PE11,	INPUT,	x),				"&
"141	(BC_1,	*,	CONTROL,	1),				" &
"140	(BC_1,	PE12,	OUTPUT3,	х,	141,	1,	Z),	" &
"139	(BC_4,	PE12,	INPUT,	X),				" &
"138	(BC_1,	*,	CONTROL,	1),				" &
"137	(BC_1,	PE13,	OUTPUT3,	Х,	138,	1,	Z),	"&
"136	(BC_4,	PE13,	INPUT,	X),				" &
"135	(BC_1,	*,	CONTROL,	1),				" &
"134	(BC_1,	PE14,	OUTPUT3,	Х,	135,	1,	Z),	" &
"133	(BC_4,	PE14,	INPUT,	X),				"&
"132	(BC_1,	*,	CONTROL,	1),				" &
"131	(BC_1,	PE15,	OUTPUT3,	Х,	132,	1,	Z),	" &
"130	(BC_4,	PE15,	INPUT,	X),				" &
"129	(BC_1,	*,	CONTROL,	1),				"&
"128	(BC_1,	PB10,	OUTPUT3,	х,	129,	1,	Z),	"&
"127	(BC_4,	PB10,	INPUT,	X),	1000 1000 100 <b>1</b> 00	1000 C		" &



# Exploring JTAG port (BS on STM32)

- Video demonstration of using JTAG boundary scan on STM32F3
- The bsr.tcl script by Paul Fertser
  - Init BS TAP
  - Scan for floating PADs
  - Scan for changed PADs after adding pull-up/down.
  - Test related control bits for given PAD. For example:
    - Bit 142 read input state
    - Bit 143 set output state
    - Bit 144 switch between input and output mode.



## Exploring JTAG port (BS on STM32)



#### Crazy idea:

#### What if we configure a pin from GPIO peripheral and test it with BS?







# Exploring JTAG port (GPIO + BS on STM32)

- Is it possible with JTAG BS to read a PAD which was configured by GPIO peripheral? Yes! At least on some SoCs
- Steps made in following video:
  - Start JTAG and halt CPU.
  - Enable CLK for GPIO controller.
  - Measure PAD with GPIO, then switch the PAD to output mode
  - Switch to the JTAG BS mode and read out PAD state



## Exploring JTAG port (GPIO + BS on STM32)

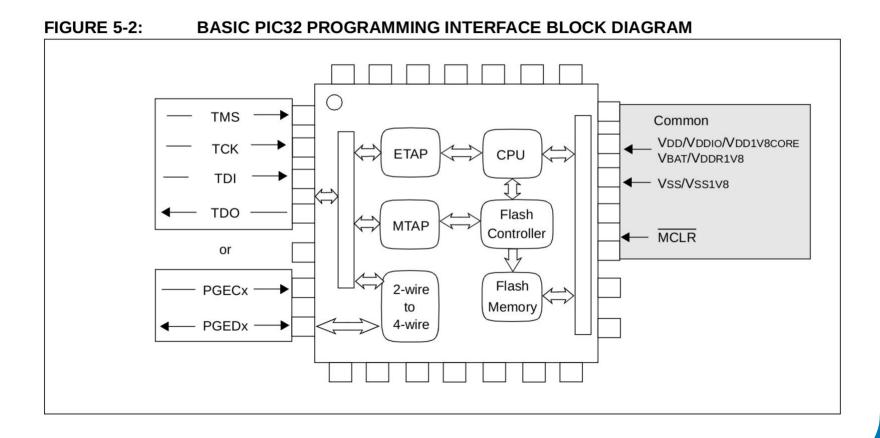


# Exploring JTAG port (GPIO + BS on PIC32)

- Same test on PIC32
- Suddenly it needed more work than expected
- PIC32xx has multiple taps but not connected in chain so BYPASS instruction is not applicable. We have here two vendor instructions: switch to MTAP and switch to ETAP
- The BS is available on MTAP



## Exploring JTAG port (GPIO + BS on PIC32)



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# Exploring JTAG port (GPIO + BS on iMX6)

- Same test on iMX6
- BS is implemented on SJC TAP
- This was fast, the BS instruction is directly connected to reset controller. Executing BS will automatically put CPU in reset state
- BS should still be possible with correctly configured bootstrap pins (see the SoC manual)



# Exploring JTAG on iMX6

- Implemented and tested TAPs for iMX6:
  - MPCore, Cortex-A9
- Not implemented or not upstreamed parts:
  - Everything else :)

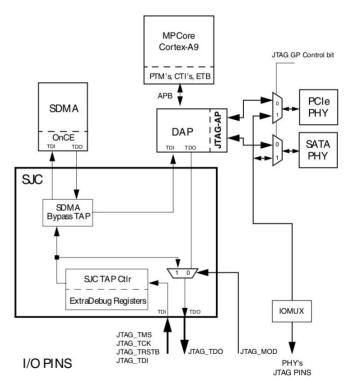


Figure 56-1. System JTAG Controller (SJC) Block Diagram



# Thank you!

#### Questions?



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